# CLC5957 12-bit, 70MSPS Broadband Monolithic A/D Converter

### **General Description**

The CLC5957 is a monolithic 12-bit, 70MSPS analog-to-digital converter. The device has been optimized for use in IF-sampled digital receivers and other applications where high resolution, high sampling rate, wide dynamic range, low power dissipation, and compact size are required. The CLC5957 features differential analog inputs, low jitter differential universal clock inputs, a low distortion track-and-hold with 0-300MHz input bandwidth, a bandgap voltage reference, data valid clock output, TTL compatible CMOS (3.3V or 2.5V) programmable output logic, and a proprietary 12-bit multi-stage quantizer. The CLC5957 is fabricated on the ABIC-V 0.8 micron BiCMOS process.

The CLC5957 features a 74dBc spurious free dynamic range (SFDR) and a 67dB signal to noise ratio (SNR). The wideband track-and-hold allows sampling of IF signals to greater than 250MHz. The part produces two-tone, dithered, SFDR of 83dBFS at 75MHz input frequency. The differential analog input provides excellent common mode rejection, while the differential universal clock inputs minimize jitter. The 48-pin TSSOP package provides an extremely small footprint for applications where space is a critical consideration. The CLC5957 operates from a single +5V power supply. Operation over the industrial temperature range of -40°C to +85°C is guaranteed. National Semiconductor tests each part to verify compliance with the guaranteed specifications.

#### **Features**

- 70MSPS
- Wide dynamic range SFDR: 74dBc SFDR w/dither: 85dBFS

SNR: 67dB

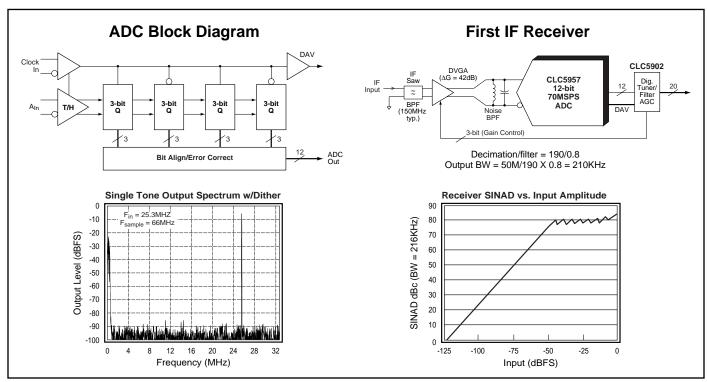
- IF sampling capability
   Input bandwidth = 0.300N
- Input bandwidth = 0-300MHz
- · Low power dissipation: 640mW
- Very small package: 48-pin TSSOP
- Single +5V supply
- Data valid clock output
- Programmable output levels: 3.3V or 2.5V

### **Applications**

- Cellular base-stations
- Digital communications
- Infrared/CCD imaging
- IF sampling
- Electro-optics
- Instrumentation
- Medical imaging
- High definition video



**Actual Size** 



#### CLC5957 Electrical Characteristics (V<sub>cc</sub>= +5V, 66MSPS; unless specified) (T<sub>min</sub> = -40°C, T<sub>max</sub> = +85°C) CONDITIONS **RATINGS UNITS NOTES PARAMETERS TEMP** MIN TYP MAX RESOLUTION Full 12 Bits 1 **DIFF. INPUT VOLTAGE RANGE** Full 2.048 **MAXIMUM CONVERSION RATE** Full 70 75 **MSPS** 1 $f_{in} = 25MHz$ , $A_{in} = -1dBFS$ +25°C 63 66 dBFS SNR 1 $f_{in} = 25MHz$ , $A_{in} = -1dBFS$ **SFDR** 1 +25°C 66 74 dBc **NO MISSING CODES** $f_{in} = 5MHz$ , $A_{in} = -1dBFS$ +25°C Guaranteed 1 DYNAMIC PERFORMANCE $A_{in} = -3dBFS$ +25°C 300 MHz large-signal bandwidth overvoltage recovery time $A_{in} = 1.5FS (0.01\%)$ +25°C 12 ns +25°C effective aperture delay (Ta) -0.41ns aperture jitter +25°C 0.3 ps(rms) **NOISE AND DISTORTION** signal-to-noise ratio (w/o 50 harmonics) $A_{in} = -1dBFS$ Full 67 dBFS $f_{in} = 5.0MHz$ $f_{in} = 25MHz$ $A_{in} = -1dBFS$ Full 60 66 dBFS $f_{in} = 75MHz$ $A_{in} = -3dBFS$ 65 dBFS Full $f_{in} = 150MHz$ $A_{in} = -15dBFS$ Full 66 dBFS $f_{in} = 250MHz$ $A_{in} = -15dBFS$ dBFS Full 66 spurious-free dynamic range $f_{in} = 5.0MHz$ $A_{in} = -1dBFS$ Full 74 dBc $f_{in} = 25MHz$ $A_{in} = -1dBFS$ 60 74 dBc Full 1 $f_{in} = 75MHz$ $A_{in} = -3dBFS$ Full 72 dBc $f_{in} = 150MHz$ $A_{in} = -15dBFS$ Full 69 dBc $f_{in} = 250MHz$ $A_{in} = -15dBFS$ Full 65 dBc intermodulation distortion $f_{in1} = 149.84MHz, f_{in2} = 149.7MHz A_{in} = -10dBFS$ +25°C 68 dBFS $f_{in1} = 249.86MHz$ , $f_{in2} = 249.69MHz$ $A_{in} = -10dBFS$ +25°C 58 dBFS dithered performance spurious-free dynamic range $A_{in} = -6dBFS$ $f_{in} = 19MHz$ +25°C dBFS 85 intermodulation distortion +25°C dBFS $f_{in1} = 74MHz, f_{in2} = 75MHz$ $A_{in} = -12dBFS$ 83 DC ACCURACY AND PERFORMANCE $f_{in} = 5MHz$ , $A_{in} = -1dBFS$ LSB differential non-linearity Full ±0.65 integral non-linearity $f_{in} = 5MHz$ , $A_{in} = -1dBFS$ Full ±1.5 LSB no missing codes $f_{in} = 5MHz$ , $A_{in} = -1dBFS$ Full Guaranteed 1 offset error Full -30 0 30 m۷ 1 %FS gain error Full 1.2 2.2 2.6 Full 2.37 1 $V_{ref}$ **ANALOG INPUTS** analog differential input voltage range Full 2.048 Vpp analog input resistance (single ended) Full 500 Ω analog input resistance (differential) Full 1000 Ω analog input capacitance (single-ended) Full 2 pF **ENCODE INPUTS (Universal)** +25°C 5 VIH V 3 +25°C ٧ 3 +25°C V differential input swing 0.2 3 **DIGITAL OUTPUTS** +25°C 0.01 output voltage logic LOW 0.4 ٧ 1 OUTLEV = 1 (open) logic HIGH +25°C 3.5 3.8 ٧ 1 2.7 OUTLEV = 0 (GND)logic HIGH +25°C 2.4 3.0 1 TIMING (C load < 7pF) 70 **MSPS** maximum conversion rate Full 75 1 minimum conversion rate +25°C **MSPS** 10 pulse width high Full 7.2 ns pulse width low Full 7.2 ns 3.0 pipeline latency Full clk cycle falling ENCODE to output change (50%) (Tod) +25°C 10 ns

+25°C

2

9.6

ns

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rising ENCODE to DAV change (50%) (Tdv)

# 

PARAMETERS	CONDITIONS	TEMP		RATINGS		UNITS	NOTES
			MIN	TYP	MAX		2
POWER REQUIREMENTS +5V supply current Power dissipation V <sub>CC</sub> power supply rejection ratio		Full Full +25°C		128 640 64	150 750	mA mW dB	1

Min/max ratings are based on product characterization and simulation. Individual parameters are tested as noted. Outgoing quality levels are determined from tested parameters.

#### **Notes**

- 1) These parameters are 100% tested at 25°C. Sample tested at full temperature range.
- Typical specifications are based on the mean test values of deliverable converters from the first three diffusion lots.
- 3) See page 7, Figure 3 for ENCODE Inputs circuit.

### Absolute Maximum Ratings

positive supply voltage ( $V_{cc}$ ) -0.5V to +6V differential voltage between any two grounds <100mV analog input voltage range GND to V<sub>cc</sub> -0.5V to +V<sub>cc</sub> digital input voltage range output short circuit duration (one-pin to ground) infinite junction temperature 175°C -65°C to 150°C storage temperature range lead solder duration (+300°C) 10sec

Note: Absolute maximum ratings are limiting values, to be applied individually, and beyond which the serviceability of the circuit may be impaired. Functional operability under any of these conditions is not necessarily implied. Exposure to maximum ratings for extended periods may affect device reliability.

### **Recommended Operating Conditions**

positive supply voltage ( $V_{cc}$ ) +5V ±5% analog input voltage range 2.048 $V_{pp}$  diff. operating temperature range -40°C to +85°C

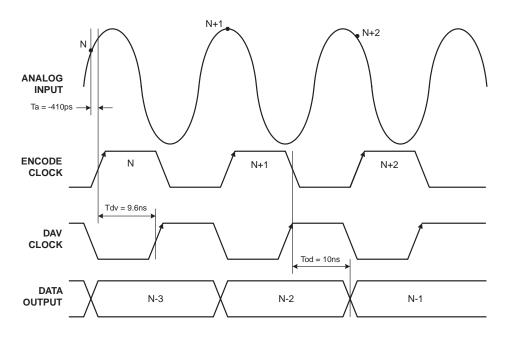
Package Thermal Resistance				
Package	$\theta_{JA}$	θЈС		
48-pin TSSOP	56°C/W	16°C/W		

### Reliability Information

Transistor count 5000

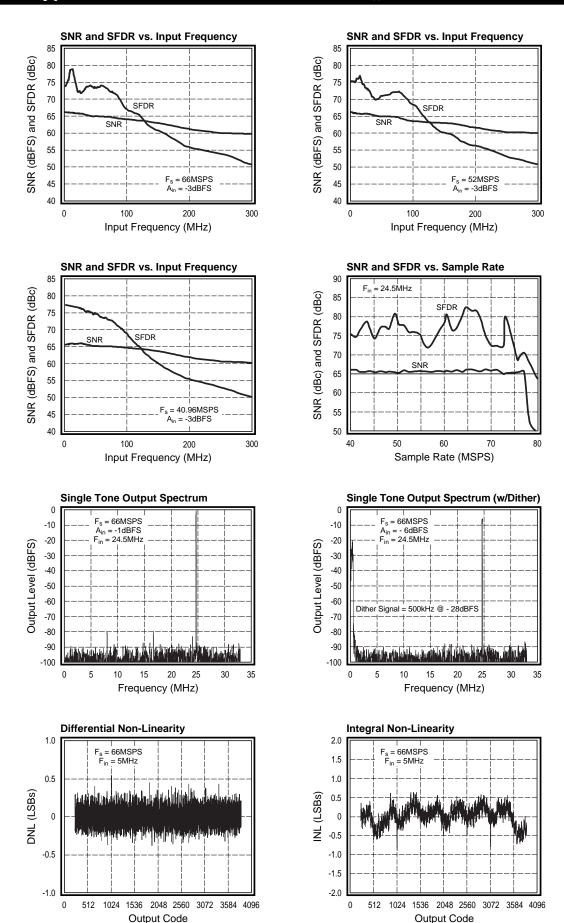
### Ordering Information

Model	Temperature Range	Description
CLC5957MTD CLC5957PCASM	-40°C to +85°C	48-pin TSSOP Fully loaded evaluation board with CLC5957 ready for test.



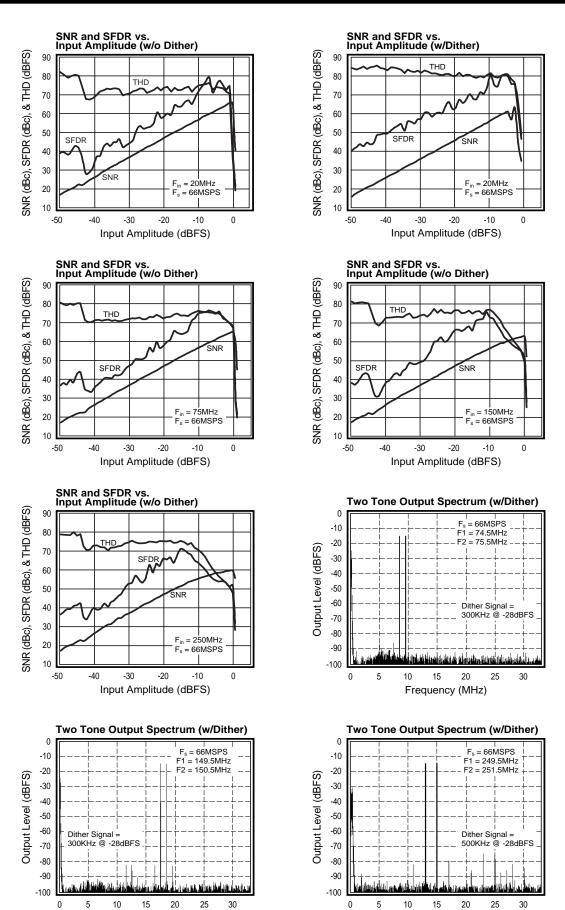
**CLC5957 Timing Diagram** 

# **CLC5957 Typical Performance Characteristics** (V<sub>cc</sub> = +5V)



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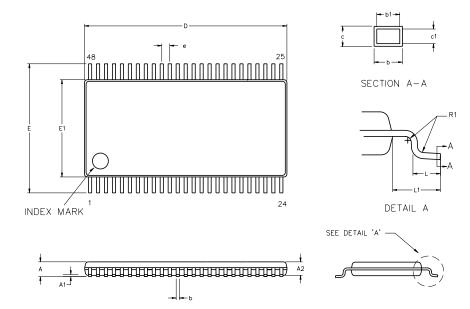
# **CLC5957 Typical Performance Characteristics** (V<sub>cc</sub> = +5V)



Frequency (MHz)

Frequency (MHz)

## **Physical Dimensions**



Symbol	Min	Max	Notes	
Α	-	1.10		
A1	0.05	0.15		
A2	0.80	1.05		
b	0.17	0.27		
b1	0.17	0.23		
С	0.09	0.20		
c1	0.09	0.16		
D	12.40	12.60	2	
E	8.1	8.1 BSC		
E1	6.00	6.20	2	
е	0.50			
L	0.50	0.75		
L1	1.00	1.00 REF		
R1	0.127			

- Notes:
   All dimensions are in millimeters.
   Dimensions D and E1 do not include mold protrusion. Allowable protrusion is 0.20mm per side.

# **CLC5957 Pin Definitions**

GND 1 GND 2 GND 3 GND 4		48 GND 47 GND 46 +DVcc 45 D11 (MSB)	$A_{IN}, \overline{A_{IN}}$	(Pin 13, 14) Differential input with a common mode voltage of +2.4V. The ADC full scale input is $1.024V_{pp}$ on each of the complimentary input signals.
+AVcc 5 +AVcc 6 +AVcc 7 GND 8 ENCODE 9	CLC5957	44 D10 43 D9 42 D8 41 D7 40 D6 39 D5	ENCODE, ENCODE	(Pin 9, 10) Differential clock where ENCODE initiates a new data conversion cycle on each rising edge. Logic for these inputs are 50% duty cycle universal differential signal (>200mV). The clock input is internally biased to $V_{CC}/2$ with a termination impedance of $2.5k\Omega$ .
GND 11 GND 12 Ain 13 Ain 14		38 +DVcc 37 +DVcc 36 GND 35 GND	D0-D11	(Pins 30-34, 39-45) Digital data outputs are CMOS and TTL compatible. D0 is the LSB and $\overline{D11}$ is the MSB. MSB is inverted. Output coding is two's complement.
GND 15 +AVcc 16		34 D4 33 D3	DAV	(Pin 27) Data Valid Clock. Data is valid on rising edge.
+AV <sub>CC</sub> 17 +AV <sub>CC</sub> 18 GND 19		32 D2 31 D1 30 D0 (LSB)	OUTLEV	(Pin 28) Output Logic 3.3V or 2.5V option. Open = 3.3V, GND = 2.5V.
GND 20 V <sub>CM</sub> 21 +AV <sub>CC</sub> 22 GND 23 GND 24		29 GND 28 OUTLEV 27 DAV 26 GND 25 GND	V <sub>CM</sub>	(Pin 21) Internal common mode voltage reference. Nominally +2.4V. Can be used for the input common mode voltage. This voltage is derived from an internal bandgap reference.
			GND	(Pins 1-4, 8, 11, 12, 15, 19, 20, 23-26, 29, 35, 36, 47, 48) circuit ground.
			+AV <sub>CC</sub>	(Pins 5-7, 16-18, 22,) +5V power supply for the analog section. Bypass to ground with a $0.1\mu F$ capacitor.
			+DV <sub>CC</sub>	(Pin 37, 38, 46) +5V power supply for the digital section. Bypass to ground with a $0.1\mu F$ capacitor.

## **CLC5957 Applications**

#### Analog Inputs and Bias

Figure 1 depicts the analog input and bias scheme. Each of the differential analog inputs are internally biased to a nominal voltage of 2.40 volts DC through a  $500\Omega$  resistor to a low impedance buffer. This enables a simple interface to a broadband RF transformer with a centertapped output winding that is decoupled to the analog ground. If the application requires the inputs to be DC coupled, the  $V_{\rm cm}$  output can be used to establish the proper common -mode input voltage for the ADC. The  $V_{\rm cm}$  voltage reference is generated from an internal bandgap source that is very accurate and stable.

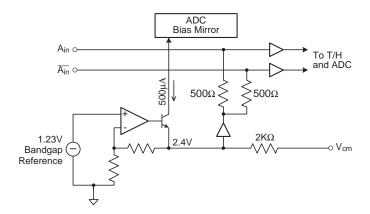


Figure 1: CLC5957 Bias Scheme

The  $V_{cm}$  output may also be used to power down the ADC. When the  $V_{cm}$  pin is pulled above 3.5V, the internal bias mirror is disabled and the total current is reduced to less than 10mA. Figure 2 depicts how this function can be used. The diode is necessary to prevent the logic gate from altering the ADC bias value.

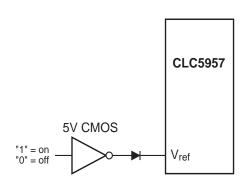


Figure 2: Power Shutdown Scheme

#### **ENCODE Clock Inputs**

The CLC5957's differential input clock scheme is compatible with all commonly used clock sources. Although small differential and single-ended signals are adequate, for best aperture jitter performance a low noise differential clock with a high slew rate is preferred. As depicted in Figure 3, both ENCODE clock inputs are internally biased to  $V_{CC}/2$  though a pair of  $5K\Omega$  resistors. The clock input buffer operates with any common-mode voltage between the supply and ground.

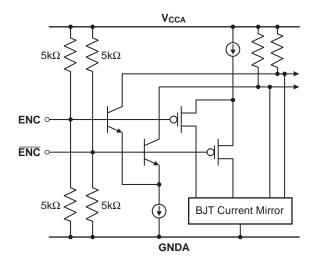


Figure 3: CLC5957 ENCODE Clock Inputs

The internal bias resistors simplify the clock interface to another center-tapped transformer as depicted in Figure 4. A low phase noise, RF synthesizer of moderate amplitude  $(1 - 4V_{DD})$  can drive the ADC through this interface.

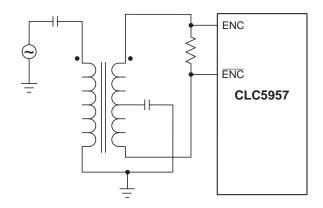


Figure 4: Transfer Coupled Clock Scheme

Figures 5 and 6 show the clock interface schemes to several other types of clock sources.

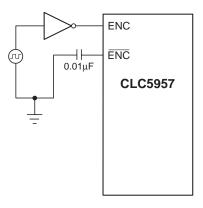


Figure 5: 5V CMOS Level Clock Scheme

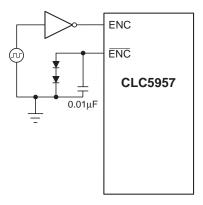


Figure 6: TTL or 3V CMOS Level Clock Scheme

#### **Digital Outputs and Level Select**

Figure 7 depicts the digital output buffer and bias used in the CLC5957. Although each of the twelve output bits uses a controlled current buffer to limit supply transients, it is recommended that parasitic loading of the outputs is minimized. Because these output transients are harmonically related to the analog input signal, excessive loading will degrade ADC performance at some frequencies.

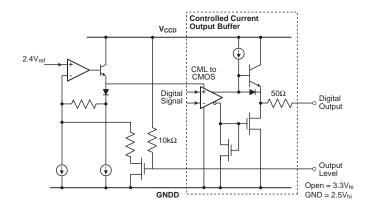


Figure 7: CLC5957 Digital Outputs

The logic high level is slaved to the internal 2.4 voltage reference. The OUTLEV control pin selects either a 3.3V or 2.5V logic high level. An internal pullup resistor selects the 3.3 volt level as the default when the OUTLEV pin is left open. Grounding the OUTLEV pin selects the 2.5V logic high level.

To ease user interface to subsequent digital circuitry, the CLC5957 has a data valid clock output (DAV). In order to match delays over IC processing variables, this digital output also uses the same output buffer as the data bits. The DAV clock output is simply a delayed version of the ENCODE input clock. Since the ADC output data change is slaved to the falling edge of the ENCODE clock, the rising DAV clock edge occurs near the center of the data valid window (or eye) regardless of the sampling frequency.

### **CLC5957 Evaluation Board**

#### **Description**

The Evaluation board for the CLC5957 allows for easy test and evaluation of the product. The part may be ordered with all components loaded and tested. The order number is the CLC5957PCASM. The user supplies an analog input signal, encode signal and power to the board and is able to take latched 12-bit digital data out of the board.

#### **ENCODE Input (ENC)**

The ENCODE input is an SMA connector with a termination of  $50\Omega$ . The encode signal is converted to an AC coupled, differential clock signal centered between V<sub>CC</sub> and ground. The user should supply a sinusoidal or square wave signal of >200mV<sub>pp</sub> and <4V<sub>pp</sub> with a 50% duty cycle. The duty cycle can vary from 50% if the minimum clock pulse width times are observed. A low jitter source will be required for IF-sampled analog input signals to maintain best performance.

#### **CLC5957 Clock Option**

The CLC5957 evaluation board is configured for use with an optional crystal clock oscillator source. The component Y1 may be loaded with a "Full-sized", HCMOS type, crystal oscillator.

#### Analog Input (AIN)

The analog input is an SMA connector with a  $50\Omega$  termination. The signal is converted from single to differential by a transformer with a 5 to 260MHz bandwidth and approximately one dB loss. Full scale is approximately 11dBm or  $2.2V_{pp}$ . It is recommended that the source for the analog input signal be low jitter, low noise and low distortion to allow for proper test and evaluation of the CLC5957.

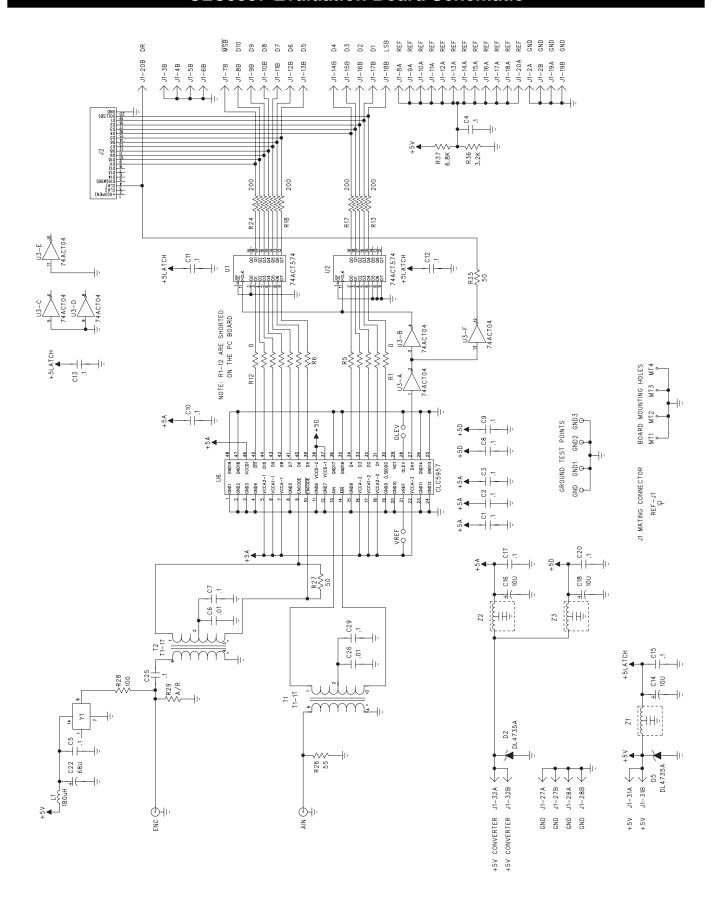
#### Supply Voltages (J1 pins 31 A&B and 32 A&B)

The CLC5957PCASM is powered from a single 5V supply connected from the referenced pins on the Eurocard connector. The recommended supplies are low noise linear supplies.

# Digital Outputs (J1 pins 7B (MSB, D11) through 18B (LSB) and 20B (Data Valid))

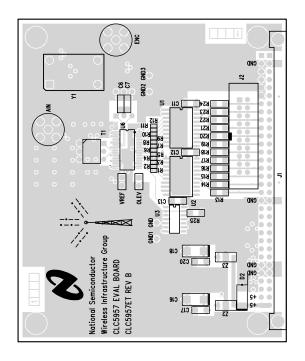
The digital outputs are provided on the Eurocard connector. The outputs are buffered by 5V CMOS latches with  $50\Omega$  series output resistors. The rising edge of Data Valid may be used to clock the output data into data collection cards or logic analyzers. The board has a location for the HP 01650-63203 termination adapter for HP 16500 logic analyzers to simplify connection to the analyzer.

### **CLC5957 Evaluation Board Schematic**

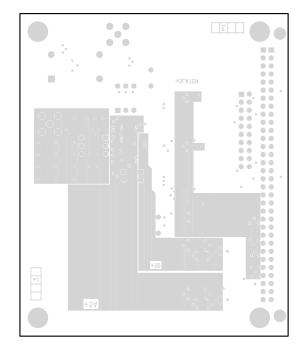


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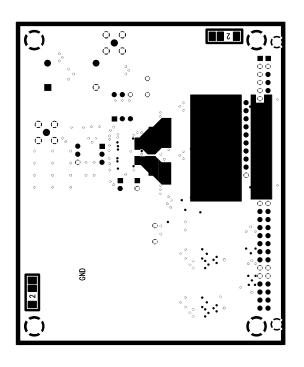
# **CLC5957 Evaluation Board Layout**



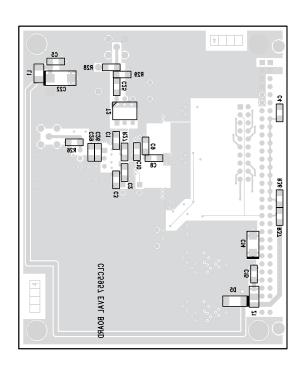
CLC5957PCASM Layer 1



**CLC5957PCASM Layer 3** 



CLC5957PCASM Layer 2



CLC5957PCASM Layer 4

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